

PCT

WORLD INTELLECTUAL PROPERTY ORGANIZATION International Bureau



INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification 6:
H01L 21/00, G05B 19/418

A1

(11) International Publication Number: WO 98/57358

(43) International Publication Date: 17 December 1998 (17.12.98)

(21) International Application Number: PCT/US98/11320
(22) International Filing Date: 8 June 1998 (08.06.98)

(31) International Publication Number: 17 December 1998 (17.12.98)

(81) Designated States: JP, KR, SG, European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).

US

(71) Applicant: APPLIED MATERIALS, INC. [US/US]; 3050

9 June 1997 (09.06.97)

Bowers Avenue, Santa Clara, CA 95054 (US).

(72) Inventor: JEVTIC, Dusan; 444 Saratoga Avenue #34B, Santa

(74) Agents: MOSER, Raymond, R., Jr. et al.; Applied Materials, Inc., P.O. Box 450A, Santa Clara, CA 95052 (US).

Published

With international search report.

Before the expiration of the time limit for amending the claims and to be republished in the event of the receipt of amendments.

(54) Title: METHOD AND APPARATUS FOR AUTOMATICALLY GENERATING SCHEDULES FOR WAFER PROCESSING WITHIN A MULTICHAMBER SEMICONDUCTOR WAFER PROCESSING TOOL

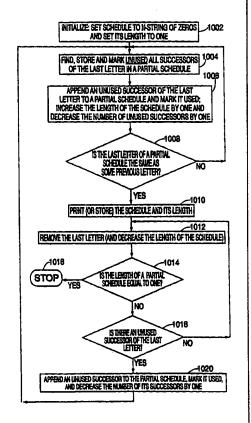
(57) Abstract

(30) Priority Data:

08/871,746

Clara, CA 95050 (US).

A method and apparatus for producing schedules for a wafer in a multichamber semiconductor wafer processing tool comprising the steps of providing a trace defining a series of chambers that are visited by a wafer as the wafer is processed by the tool; initiatizing a sequence generator with a value of a variable defining initial wafer positioning within the tool; generating all successor variables for the initial variable value to produce a series of values of the variable that represent a partial schedule; backtracking through the series of variables to produce further partial schedules; and stopping the backtracking when all possible variable combinations are produced that represent all possible valid schedules for the trace. All the possible schedules; are analyzed to determine a schedule that produces the highest throughput of all the schedules.



oils.

FOR THE PURPOSES OF INFORMATION ONLY

Codes used to identify States party to the PCT on the front pages of pamphlets publishing international applications under the PCT.

AL	Albania	ES	Spain	LS	Lesotho	SI	Slovenia
AM	Armenia	FI	Finland	LT	Lithuania	SK	Slovakia
ΑT	Austria	FR	France	LU	Luxembourg	SN	Senegal
AU	Australia	GA	Gabon	LV	Latvia	SZ	Swaziland
ΑZ	Azerbaijan	GB	United Kingdom	MC	Monaco	TD	Chad
BA	Bosnia and Herzegovina	GE	Georgia	MD	Republic of Moldova	TG	Togo
BB	Barbados	GH	Ghana	MG	Madagascar	TJ	Tajikistan
BE	Belgium	GN	Guinea	MK	The former Yugoslav	TM	Turkmenistan
BF	Burkina Faso	GR	Greece		Republic of Macedonia	TR	Turkey
BG	Bulgaria	HU	Hungary	ML	Mali	TT	Trinidad and Tobago
a J	Benin	ΙE	Ireland	MN	Mongolia	UA	Ukraine
BR	Brazil	IL	Israel	MR	Mauritania	UG	Uganda
8 Y	Belarus	IS	Iceland	MW	Malawi	US	United States of Americ
CA	Canada	ΙT	Italy	MX	Mexico	UZ	Uzbekistan
CF	Central African Republic	JP	Japan	NE	Niger	VN	Viet Nam
CG	Congo	KE	Кепуа	NL	Netherlands	YU	Yugoslavia
CH	Switzerland	KG	Kyrgyzstan	NO	Norway	zw	Zimbabwe
CI	Côte d'Ivoire	KP	Democratic People's	NZ	New Zealand		
CM	Cameroon		Republic of Korea	PL	Poland		
CN	China	KR	Republic of Korea	P T	Portugal		
CU	Cuba	KZ	Kazakstan	RO	Romania		
CZ	Czech Republic	LC	Saint Lucia	RU	Russian Federation		
DE	Germany	LI	Liechtenstein	SD	Sudan		
DK	Denmark	LK	Sri Lanka	SE	Sweden		
ER	Estonia	LR	Liberia	SG	Singapore		

-1-

PCT/US98/11320

METHOD AND APPARATUS FOR AUTOMATICALLY GENERATING SCHEDULES FOR WAFER PROCESSING WITHIN A MULTICHAMBER SEMICONDUCTOR WAFER PROCESSING TOOL

5 BACKGROUND OF THE INVENTION

WO 98/57358

1. Field of the Invention

The present invention relates to a multiple chamber wafer processing tool and, more particularly, to a method and apparatus for automatically generating a schedule(s) for a semiconductor wafer within a multiple chamber semiconductor wafer processing tool.

2. Description of the Background Art

Semiconductor wafers are processed to produce
15 integrated circuits using a plurality of sequential process

steps. These steps are performed using a plurality of process chambers. An assemblage of process chambers served by a wafer transport robot is known as a multiple chamber semiconductor wafer processing tool or cluster tool. FIG. 1

20 depicts, in part, a schematic diagram of an illustrative cluster tool known as the Endura® System manufactured by Applied Materials, Inc. of Santa Clara, California.

The cluster tool 100 contains, for example, four process chambers 104, 106, 108, 110, a transfer chamber 112,

- 25 a preclean chamber 114, a buffer chamber 116, a wafer orienter/degas chamber 118, a cooldown chamber 102, and a pair of loadlock chambers 120 and 122. Each chamber represents a different stage or phase of semiconductor wafer processing. The buffer chamber 116 is centrally located
- 30 with respect to the loadlock chambers 120 and 122, the wafer orienter/degas chamber 118, the preclean chamber 114 and the cooldown chamber 102. To effectuate wafer transfer amongst these chambers, the buffer chamber 116 contains a first robotic transfer mechanism 124. The wafers 128 are
- transport cassette 126 that is placed within one of the loadlock chambers 120 or 122. The robotic transport mechanism 124 transports the wafers 128, one at a time, from the cassette 126 to any of the three chambers 118, 102, or

114. Typically, a given wafer is first placed in the wafer orienter/degas chamber 118, then moved to the preclean chamber 114. The cooldown chamber 102 is generally not used until after the wafer is processed within the process chambers 104, 106, 108, 110. Individual wafers are carried upon a wafer transport blade 130 that is located at the distal end of the first robotic mechanism 124. The transport operation is controlled by a sequencer 136.

The transfer chamber 112 is surrounded by and has

10 access to the four process chambers 104, 106, 108 and 110 as

well as the preclean chamber 114 and the cooldown chamber

102. To effectuate transport of a wafer amongst the

chambers, the transfer chamber 112 contains a second robotic

transport mechanism 132. The mechanism 132 has a wafer

15 transport blade 134 attached to its distal end for carrying

the individual wafers. In operation, the wafer transport

blade 134 of the second transport mechanism 132 retrieves a

wafer from the preclean chamber 114 and carries that wafer

to the first stage of processing, for example, a physical

20 vapor deposition (PVD) stage within chamber 104. Once the

wafer is processed and the PVD stage deposits material upon

the wafer, the wafer can then be moved to a second stage of

processing and so on.

Once processing is complete within the process

25 chambers, the transport mechanism 132 moves the wafer from
the process chamber and transports the wafer to the cooldown
chamber 102. The wafer is then removed from the cooldown
chamber using the first transport mechanism 124 within the
buffer chamber 116. Lastly, the wafer is placed in the

30 transport cassette 126 within the loadlock chamber 122.

More generally, a cluster tool contains n chambers, denoted by C_1, C_2, \ldots, C_n , one or more transfer chambers (robots) 112 and 116, and one or more loadlocks 120 and 122. The exact arrangement of chambers, robots and loadlocks is referred to as the "configuration" of the tool. A wafer Wa to be processed is taken from a loadlock, placed successively into various chambers as each chamber performs a particular process upon the wafer.

A wafer's trace is the trajectory of a particular wafer through the cluster tool; that is, a trace is the order in which chambers are visited by a wafer (not necessarily C_{i,1} after C_i). This should be distinguished from the term "processing sequence" which is the order of applying processes (recipes) to a wafer. If more than one chamber performs the same process (parallel chambers), a given processing sequence may be satisfied by several different traces.

'A wafer which completes its processing sequence and is returned to the loadlock is said to be processed by the tool. Roughly speaking, a tool's throughput is the number of wafers processed by the tool per unit of time. That is, if the tool needs t seconds to process n_t wafers, then

$$S_{t} := \frac{n_{t}}{t} \tag{3}$$

is the tool's throughput measured in the interval [0,t].

There are many ways to improve the tool's throughput for a given processing sequence. However, one important improvement is to use efficient scheduling routines for a 20 given processing sequence.

The optimization of scheduling involves the choice of criteria used in deciding when to transfer a wafer from one chamber into the next (and which wafers should be moved, if any, prior to that move). A routine which schedules the movement of wafers through the cluster tool (based on a given processing sequence) is referred to as a "scheduling routine."

The steady-state throughput of a tool under scheduling routine A is denoted by S(A). If n>1 then, depending on a given processing sequence, one may consider a number of scheduling routines that fulfill the processing sequence. The routine which maximizes the value of throughput is deemed the "optimum" routine and the maximum attainable value of throughput is known as the tool's "capacity." That is, if A is the set of all possible scheduling routines for a given processing sequence, then A* is optimum if

$$S(A^*) = \max\{S(A) \mid A \in A\}$$
 (4)

· WO 98/57358 PCT/US98/11320 -4-

Clearly, the tool's capacity $S(A^*)$ depends on a given processing sequence as well as on chamber and robot parameters within the processing sequence. The problem of finding efficient scheduling routines for a given processing 5 sequence (especially, finding optimum routines, where possible) is of considerable practical importance.

Presently there is not an automatic method of determining the best schedule, given a particular trace, that provides the highest throughput for that trace.

10 Typically, a trial and error method is used until a schedule is determined that provides a sufficient throughput. However, the sufficient throughput may not be the best throughput that is possible for a given trace.

Therefore, a need exists in the art for a method and 15 apparatus that determines all possible schedules given a particular trace and, using a throughput modeling program determines the throughput for each of the possible schedules and selects a schedule for use within a cluster tool that provides the maximum throughput for the given trace. 20.

SUMMARY OF THE INVENTION

The disadvantages heretofore associated with the prior art are overcome by an invention of a method and apparatus for determining all possible schedules that accomplish a 25 given trace, applying a throughput model to each of the schedules, and determining the schedule or schedules that result in the highest throughput.

More specifically, the invention uses a set of deterministic rules to compute the various schedules. 30 First, a schedule is defined as a series of "letters" that form a "word". Each letter in the word defines a possible positioning of wafers within a cluster tool. Of course, the positioning of the wafers within the tool must fulfill the trace, i.e., each letter must follow from a predecessor 35 letter in accordance with a particular set of rules that define the trace.

Given a letter (input letter) representing present wafer positions, the invention computes all possible successor wafer positions, i.e., all possible valid

successor letters, as well as the total number of successors for the input letter. The invention provides individual "modules" for successor computation for serial traces, parallel traces, and mixed traces. Using a backtracking technique to repeatedly compute, from any letter, all possible successor letters, and then compute all possible successor letters of the successor letters, a schedule tree is derived. The schedule tree contains all possible schedules that will fulfill a given trace. Each and every schedule can then be modeled to determine the expected throughput of each schedule. By comparing the throughput associated with each schedule, an optimal schedule or schedules is identified.

15 BRIEF DESCRIPTION OF THE DRAWINGS

The teachings of the present invention can be readily understood by considering the following detailed description in conjunction with the accompanying drawings, in which:

- Fig. 1 depicts a schematic diagram of a multiple

 20 chamber semiconductor wafer processing tool being controlled
 by a sequencer that operates using scheduling routines

 generated by a schedule generator in accordance with the
 present invention;
- Fig. 2 depicts block diagram of schedule generator that performs operative steps in accordance with the present invention;
 - Fig. 3 depicts a flow diagram of a 4-chamber serial trace;
- Fig. 4 depicts a flow diagram of a 4-chamber mixed 30 trace;
 - Fig. 5 depicts a flow diagram of a schedule optimization routine of the present invention;
 - Fig. 6 depicts a tree diagram representing all possible schedules for a 2-chamber serial trace;
- FIG. 6A depicts a schematic diagram of a 2-chamber serial trace of FIG. 6 showing a wafer in position (1,0);
 - Fig. 7 depicts a tree diagram representing all possible schedules for a 3-chamber serial trace;

FIG. 7A depicts a schematic diagram of a 3-chamber serial trace of FIG. 7 showing a wafer in position (0,1,0);

Fig. 8 depicts a tree diagram representing all possible schedules for a trace: $LL-C_1-(C_2,C_3)-LL$;

FIG. 8A depicts a schematic diagram of a 3-chamber 5 mixed trace of FIG. 8 showing a wafer in position (1,1,0);

Fig. 9 depicts a tree diagram containing partial schedules as constructed using the present invention; and

Fig. 10 depicts a flow diagram of a routine for 10 producing all possible schedules for a given trace using a backtracking technique.

To facilitate understanding, identical reference numerals have been used, where possible, to designate identical elements that are common to the figures.

15

DETAILED DESCRIPTION

A. Overview of the Invention

As discussed above, FIG. 1 depicts, in part, a schematic diagram of a conventional $\operatorname{multiple}_i$ chamber 20° semiconductor wafer processing tool. The depicted cluster tool 100 is controlled by a sequencer that executes the scheduling routines determined by the present invention. The present invention is embodied in a schedule generator 50 that produces scheduling routines which are executed by the 25 sequencer 136.

FIG. 2 depicts a block diagram of the scheduling generator 50 that produces the scheduling routines executed by the sequencer to control the cluster tool 100 of FIG. 1. Additionally, the schedule generator 50 operates to

30 determine an optimal sequencing routine for a given processing sequence and tool configuration. Although, the schedule generator is shown to remotely produce schedules and download one or more schedules to the sequencer, those skilled in the art will understand that the invention could

35 be practiced on a processor within the sequencer.

The schedule generator 50 contains a microprocessor 200 as well as memory 202 for storing a schedule generation routine 210, a schedule optimization routine 212 and the scheduling routine(s) generated by routines 210 and 212.

.

The microprocessor 200 cooperates with conventional support circuitry 206 such as power supplies, clock circuits, cache, and the like as well as circuits that assist in executing the software routines. As such, it is contemplated that 5 some of the process steps discussed herein as software processes may be implemented within hardware, e.g., as circuitry that cooperates with the microprocessor to perform various process steps. The schedule generator 50 also contains input/output circuitry 208 that forms an interface 10 between conventional input/output (I/O) devices 214 such as a keyboard, mouse, and display as well as an interface to the sequencer. Although the schedule generator 50 is depicted as a general purpose computer that is programmed to determine scheduling routines in accordance with the present 15 invention, the invention can be implemented in hardware as an application specific intergrated circuit (ASIC). As such, the process steps described herein are intended to be broadly interpreted as being equivalently performed by software, hardware, or a combination thereof.

The automatic schedule generator 50 of the present invention executes a schedule generation routine 210 that generates all possible schedules for a given trace. A schedule optimization routine 212 facilitates an automated process of producing an optimum schedule for a given cluster tool using an exhaustive search of all possible schedules.

The following definitions are used throughout this disclosure:

"Tool configuration" describes physical placement of chambers within a cluster tool. For example, the tool may 30 have chambers C₁, C₂, C₃ and C₄, a LoadLock (LL) as well as one or more robots.

"Process sequence" is the order in which processes are applied to a given wafer. For example, P_n is the name of the n-th process (e.g., etch) and, P_1 , P_2 , P_3 , (which also may be written as $P_1 \rightarrow P_2 \rightarrow P_3$) is a process sequence.

"Processing capability" of a cluster tool is the result of mapping a required process sequence onto the set of chambers within the tool. The image of this mapping is

called a "trace". For example, a process sequence $P_1 \rightarrow P_2 \rightarrow P_3$ may be mapped onto four chambers $\mathrm{C_1}$, $\mathrm{C_2}$, $\mathrm{C_3}$ and $\mathrm{C_4}$ to yield a

5 $LL \rightarrow C_1 \rightarrow (C_2 \lor C_3) \rightarrow C_4 \rightarrow LL$.

Note that processes P_1 and P_3 are mapped into chambers C_1 and C_4 , respectively, while process P_2 is mapped into $C_2 \lor C_3$ (the process P_2 is performed in both C_2 and C_3). Chambers C_2 and C_3 are said to be parallel because a wafer visits (is placed 10 into) either C2 or C3 (but not both). In other words, the sign \vee in $C_2 \vee C_3$ represents an exclusive OR function.

"Stage" is a set of one or more chambers which correspond to the same process. Wafers visit exactly one chamber from a given stage. The notation $(C_x \lor C_y \lor C_z)$ means 15 that wafers can move to either chambers C_x or C_y or C_z , but only into one of the chambers. That is, $(C_x \lor C_y \lor C_z)$ is a stage comprised of three "parallel" chambers.

Generally speaking, the term "schedule" means a finite and repeatable sequence of wafer and robot movements through 20 the cluster tool. More formally, let S be the set of all possible wafer and robot states. A string of symbols (letters) from a finite set of states S is referred to as a word. Symbols are represented as letters from the alphabet For example, if $S = \{0,1\}^2$, then (0,0), (0,1), (1,0), and

25 (1,1) are all possible letters in alphabet S and (0,1)(1,1)(0,1) is a word having a length of 3 letters over S. Each letter identifies the instantaneous state of the tool. For example, as is discussed in detail below, a letter may define the particular positioning of a wafer or 30 wafers within a tool at a particular point in the trace.

Broadly speaking, whatever the specific alphabet, a schedule S is represented as a word,

which starts and ends with the same letter (e.g., x), this is the only repeated letter, and a successor v of a given letter u must satisfy alphabet dependent rules, i.e., rules which define a valid trace.

Traces are available in three different configurations, A trace is a parallel trace if it is comprised of exactly one stage; a trace is a serial trace if each stage has exactly one chamber and a trace is a mixed trace if it is neither serial nor parallel. (Clearly, to have a mixed trace, the number of chambers in the trace is at least three.) A trace is said to be knotted if there is a chamber whose name appears more than once in the trace (that is, the corresponding process sequence contains a processing loop). To illustrate, Figs. 3 and 4 schematically depict 4-stage serial and mixed traces, respectively.

Fig. 5 depicts a high level flow diagram of the schedule optimization routine 212. The optimization routine contains a schedule generation routine 210 that produces all possible schedules in an alphabet induced by a given trace.

20 Routine 212 is an automated process that performs the following steps:

- a) Input a trace L (step 500),
- b) Produce all possible schedules over L (routine 210)
 using a two step process, where the first step
 (step 508) generates all possible successor
 positions (letters) to which a wafer can be moved
 from a present position (letter) and the second
 step (step 510) uses a backtracking technique to
 change wafer positions such that other successor
 positions (letters) can be computed by step 508,
 - c) Evaluate each of the schedules in (b) with respect to throughput (for a given set of robot and process parameters) (step 504),
- d) Record a schedule or a set of schedules which have the highest throughput for the given trace L (step 506).

Since step (c) requires a throughput simulation program, for computational efficiency, steps (a), (b) and (d) are generally incorporated into the simulation program.

A plurality of embodiments of the present invention are discussed below in Sections B, C, D and E of this disclosure. Specifically, the definitions of a schedule in a {0,1}ⁿ alphabet, rules for generating successors of a given letter, and modules needed for computation of successors are given in Section B for a serial trace and Section C for mixed and parallel traces. In Section D, these processes are extended to include robot utilization in the computations. Lastly, a generalized backtracking routine for generating all possible schedules from a given trace, applicable to any trace with or without a robot, is presented in Section E.

B. Schedule Generation for Serial Traces

An n-chamber serial trace (as illustratively depicted in FIG. 3), comprised of chambers C_1, C_2, \ldots, C_n , is associated with an n-tuple from the alphabet $\{0,1\}^n$. If \bar{x} is such a tuple, then, for $i=1,2,\ldots,n$; $\bar{x}[i]=0$, if chamber C_i is empty, and $\bar{x}[i]=1$, if C_i contains a wafer. In accordance with this representation, a schedule S is a finite string of binary n-tuples,

$$S = \overline{x} \dots \overline{u} \overline{v} \dots \overline{x}$$

which starts and ends with the same binary n-tuple and this 25 is the only repeated n-tuple in the string. In addition, any two consecutive n-tuples \bar{u} and \bar{v} in the string, \bar{v} being a successor of \bar{u} , differ in at most two coordinates and are related in accordance with the following rules:

- s_1) If u[1]=0, then v[1]=1. For all k>1, v[k]=u[k]. (This corresponds to a wafer being moved from the loadlock into C_1 .)
 - s_2) If u[n]=1, then v[n]=0. For all k<n, v[k]=u[k]. (This corresponds to a wafer being moved from C_n into the loadlock).

- s₃) If, for some $k \notin \{0,n\}$, $\overline{u}[k]=1$ and $\overline{u}[k+1]=0$, then $\overline{v}[k]=0$ and $\overline{v}[k+1]=1$. For all $i \notin \{k,k+1\}$, $\overline{v}[i]=\overline{u}[i]$. (This corresponds to a wafer being moved from C_k into $C_{k\neq 1}$)
- 5 FIG. 6 illustrates all possible schedules available (i.e., two schedules) in a 2-chamber serial trace. FIG. 6A depicts a schematic diagram of the 2-chamber serial trace of FIG. 6 having a wafer in position represented by the 2-tuple (1,0). These n-tuples are referred to herein as the coordinates of 10 wafer positioning. From position (1,0), the schedule of FIG. 6 dictates that the wafer is next moved to a position represented by the 2-tuple (0,1), i.e., a wafer is now in chamber C_2 and no wafer is in chamber C_1 . Thereafter, the schedule may follow one of two paths, either the wafer in C_2 15 is moved to the loadlock (a wafer positioning that is represented by 2-tuple (0,0)) or another wafer is moved into chamber C_1 (a wafer positioning that is represented by 2-tuple (1,1)). As such, each 2-tuple represents a set of possible positions for a wafer or wafers that validly 20 fulfill a step in the trace.

Similarly, FIG. 7, illustrates the seven possible schedules available in a 3-chamber serial trace and FIG. 7A depicts a schematic diagram of the trace of FIG. 7 having a wafer positioning represented by the 3-tuple (0,1,0). From Fig. 7, the strings

$$\begin{split} S_{p} &= (1,1,1) \; (1,1,0) \; (1,0,1) \; (0,1,1,) \; (1,1,1) \\ S_{w} &= (1,0,0) \; (0,1,0) \; (0,0,1) \; (0,0,0) \; (1,0,0) \\ S_{x} &= (1,0,1) \; (0,1,1) \; (0,1,0) \; (1,1,0) \; (1,0,1) \; . \end{split}$$

represents particular scheduling routines that are generated 30 by the schedule generator for a three chamber serial trace.

Such schedules may contain a set of robot and chamber parameters that yield higher or lower throughput than other schedules in the set of all schedules. As such, the only way to determine an optimum schedule is to examine the throughput under all possible schedules and, using the optimization routine, determine which of the schedules is optimal.

As mentioned above, the 2ⁿ binary n-tuples (position coordinates) are regarded as letters from the alphabet $\{0,1\}^n$. A finite string of letters is referred to as a word. For example, strings S_p , S_w , and S_x are all 5-letter words.

5 In this terminology, a partial schedule S of length k is a k-letter word S(1)S(2)...S(k) in which next letter S(i+1) depends only on the previous letter S(i), i=1,2,...,k-1, and is built according to rules (s_1) , (s_2) , and (s_3) stated above. In accordance with these rules, all letters in a partial schedule are different. A full schedule is a word W(1)W(2)...W(n) such that W(1)W(2)...W(n-1) is a partial schedule and W(n)=W(1). For example, the word W=(1,1,1)(1,1,0)(1,0,1)(0,1,1) is a partial schedule, where W(1)=(1,1,1) and W(4)=(0,1,1). (Generally, if $W=\overline{u_1}\overline{u_2}...\overline{u_k}$, then $W(i)=\overline{u_1}$).

From the definition of a schedule, if $\overline{u_1u_2...u_k}$ is a partial schedule, then $\overline{u_1u_2...u_k}$ $\overline{u_ku_{k+1}}$ is also a schedule (partial or full) provided $\overline{u_{k+1}}$ is obtained from $\overline{u_k}$ according to rules $(s_1), (s_2)$, and (s_3) . A given letter $\overline{u_k}$ may have anywhere from 1 to $\lfloor n/2 \rfloor + 1$ successors $\overline{u_{k+1}}$. The number of successors (variable nmb below) is easily determined by the following function:

```
function SerCount(\overline{u}_k:letter): integer;

var

i, nmb:integer;

begin

nmb:=0

for i:=1 to n-1

if \overline{u}_k[i]=1 and \overline{u}_k[i+1]=0

then nmb:=nmb+1;

nmb:=nmb+\overline{u}_k[n]+((1+\overline{u}_k[1]) \pmod{2})

return (nmb)

end;
```

where $SerCount(\bar{u}_k)$ represents the number of successors of \bar{u}_k in a serial n-chamber trace. Since, in an exhaustive search, all the successors are examined, the foregoing pseudo-code determines the total number of successor letters that must be computed to complete an exhaustive search.

-13

Generating all SerCount(u) successors of a given letter u is not particularly difficult. As each successor of u is generated, it is stored in a binary matrix Z that has SerCount(u) rows and (n+1) columns. The last column of Z is reserved for a Boolean variable that is set to true if the successor was used in a partial schedule and is set to false if the successor was not used. This entry is used later in the backtracking routine (discussed below with reference to FIG. 10) that generates all possible schedules for a given trace. The successors of a given letter are determined by the following function.

```
function SerGenerator(\overline{u}:letter): matrix;
                      var
15
                          i:integer;
                      begin
                          if \overline{u}[1] = 0 then begin
                              copy (\overline{u}, \overline{v});
                              \nu[1] = 1;
20
                              store(\overline{\nu}, Z);
                          end;
                          if \overline{u}[n] = 1 then begin
                              copy (\bar{u}, \bar{v});
                              v[n] = 0;
25
                             store (\bar{\nu}, z):
                             for i:=1 to n-1
                             if \overline{u}[i]=1 and \overline{u}[i+1]=0 then begin
                                  copy (\bar{u}, \bar{v});
30
                                  v[i]=0; v[i+1]:=1;
                                  store (\overline{\nu}, Z);
                             end:
                             return (Z);
                     end:
35
```

There are two functions which are used repeatedly in the above pseudo-code. Function $copy(\overline{u},\overline{v})$ returns letter \overline{u} that is a replica of letter \overline{v} . This manner of implementing rules (s_1) , (s_2) , and (s_3) , in which the routine first copies \overline{u} into \overline{v} and then modifies \overline{v} , is not inefficient because \overline{u} and \overline{v} differ in at most two coordinates. Function store (\overline{v},Z) copies letter \overline{v} into a proper row of matrix Z. Note that in the above module, the

routine copies a binary n-tuple twice; clearly, in implementation, the routine copies the successor of \overline{u} (slightly altered n-tuple \overline{u}) into the proper row of matrix Z directly.

- Using the foregoing pseudo-code and given a letter \bar{u} in a serial trace, the pseudo-code generates all possible successor letters of \bar{u} and stores them in matrix Z. For example, in FIG. 7, given the letter (0,0,0), the pseudo-code produces a string of valid successor letters,
- e.g., letters (1,0,1), (0,1,0), (1,1,0), and (0,0,0). Given a different initial letter, a different valid set of successors is produced, e.g., letter (0,1,0) may produce letters (1,1,0), (1,0,1), (1,0,0) and (0,1,0).
- The representation of an n-chamber mixed trace by a binary n-tuple is slightly more involved because exactly one chamber from a given stage is visited by a wafer and there are no wafer transfers within the stage. Thus, the schedule generation routine must recognize different stages as well as parallel chambers within a stage. FIG. 4 depicts an illustrative mixed trace containing four stages with six chambers, where chambers C₁ and C₄ are serial and chamber pairs C₂(a), C₂(b) and C₃(a), C₃(b) are parallel.
- Without loss of generality, it is assumed that an n-chamber mixed trace is comprised of k successive stages, $F_1, F_2, \ldots, F_k, k \le n$. If $1, 2, \ldots, n$ are positions in a binary n-tuple \bar{x} that corresponds to chambers C_1, C_2, \ldots, C_n , respectively, then positions $1, 2, \ldots, |F_i|$ corresponds to
- chambers in stage 1, positions $|F_1|+1,|F_1|+2,...,|F_1|+|F_2|$ correspond to chambers in stage 2, and so on. If chamber C_1 belongs to stage F_t , then position i in the corresponding associated binary n-tuple \bar{x} belongs to F_t and $i \in F_t$ (while, in fact, i is one of the consecutive $|F_i|$ positions in \bar{x}).
- In this representation, a schedule is a finite string of binary n-tuples which starts and ends with the same

binary n-tuple. This is the only repeated letter in the word. In addition, if $\overline{\nu}$ is a successor of \overline{u} , then \overline{u} and $\overline{\nu}$ differ in at most two coordinates and the following rules define the relationship of \overline{u} and $\overline{\nu}$:

5

- \mathbf{m}_1) If for some $i \in F_1$, $\overline{u}[i] = 0$, then $\overline{v}[i] = 1$. For all $k \neq i$, $\overline{v}[k] = \overline{u}[k]$ (This corresponds to a wafer being moved from the loadlock into stage 1.)
- , m_2) If for some $i \in F_k$, $\overline{u}[i] = 1$, then $\overline{v}[i] = 0$. For all $j \neq i$, $\overline{v}[j] = \overline{u}[j]$. (This corresponds to a wafer being moved from the last stage F_k into the loadlock).
- m₃) If for some $i \in F_t$ and some $j \in F_{t+1}$, $\overline{u}[i] = 1$ and $\overline{u}[j] = 0$, then $\overline{v}[i] = 0$ and $\overline{v}[j] = 1$. For all $r \notin \{i, j\}$, $\overline{v}[r] = \overline{u}[r]$. (This corresponds to a wafer being moved from stage F_t into the next stage F_{t+1} .)

In determining the number of successors of a given letter \overline{u} , it will be handy to define a sequence $M_0=0$ and

 $M_{i} = |F_{1}| + |F_{2}| + \cdots + |F_{i}|,$

where $|F_i|$ is the size (number of chambers) of stage F_t . The above sequence reflects the partition of the index set of \bar{u} into stages. Clearly, $M_k=n$, where n is the number of chambers. The number of successors of \bar{u} is determined by the following function:

function MixCount (\overline{u} :letter):integer;

t, i, j, nmb:integer;

begin

nmb:=0

for i:=1 to M_1 if $\overline{u}[i] = 0$ then nmb:=nmb+1

for $j:=1+M_{k-1}$ to M_k if $\overline{u}[i] = 1$ then nmb:=nmb+1

for t:=1 to k-1

30

```
for i:=1+M_{t-1} to M_t

for j:=1+M_t to M_{t+1}

if \overline{u}[i]=1 and \overline{u}[j]=0

then nmb:=nmb+1;

return (nmb)

end;
```

Obviously, if M_t =t and k=n in the above pseudo-code, then $\operatorname{MixCount}(\overline{u})$ becomes $\operatorname{SerCount}(\overline{u})$. Also, for a pure parallel n-chamber trace, due to k=1, the 3-nested "for" statements in the above pseudo-code are null; by joining the first two loops (since there is just one stage), the pseudo-code reduces to:

```
function ParCount($\overline{u}$: letter): integer;

var

i, nmb: integer;

begin

nmb:=0;

for i:=1 to n

if $\overline{u}[i] = 0$ or $\overline{u}[i] = 1$

then nmb:=nmb+1;

return (nmb)

end;
```

which always returns nmb = n. Thus, in a pure parallel n-chamber trace, any given letter has n successors.

A function that generates and stores all successors of a given letter in a mixed trace is:

```
function MixGenerator(\bar{u}:letter):matrix;
                          t, i, j: integer;
                     begin
35
                          for i:=1 to M_1
                              if \overline{u}[i] = 0 then begin
                              copy (\bar{u}, \bar{v});
                              \overline{V}[i] := 1;
                              store(\bar{v}, z)
40
                         end;
                         for j:=1+M_{k-1} to M_k
                              if \overline{u}[j]=1 then begin
                              copy(\bar{u}, \bar{v});
                              可j) := 0;
45
                              store(\overline{\nu},Z)
                         end;
                         for t:=1 to k-1
```

```
for i:=1+M_{t-1} to M_t

for j:=1+M_t to M_{t+1}

if \overline{u}[i]=1 and \overline{u}[j]=0 then begin

copy (\overline{u},\overline{v});

\overline{v}[i]:=0; \overline{v}[j]:=1;

store(\overline{v},Z)

end;

return (Z);

end;
```

10

Functions copy (\bar{u}, \bar{v}) and store (\bar{v}, Z) are the same as in the corresponding routine for serial traces. (Note that this time matrix Z has $MixCount\bar{u}$ rows and (n+1) columns.) Again, if M_t =t and k=n in the above function, then

MixGenerator(\bar{u}) becomes SerGenerator(\bar{u}). For pure parallel traces, due to k=1, a function that generates successors of a given letter \bar{u} is:

```
function ParGenerator(\bar{u}:letter):matrix;
20
                         i:integer;
                    begin
                         for i:=1 to n
                         begin
25
                              copy (\bar{u}, \bar{v});
                             if \overline{u}[i] = 1
                             then \bar{v}[i] := 0
                             else \overline{v}[i]:=1
                             store (\bar{\nu}, z)
30
                         end;
                         return (Z)
                    end;
```

Note the similarity between functions that count

successors and functions that generate successors. In fact,
conditions for identifying a successor are identical in both
types of function; the difference is what is performed once
the condition is detected.

FIG. 8 depicts an illustrative schedule tree for a 3-chamber mixed trace, (e.g., $LL\rightarrow C_1\rightarrow (C_2\lor C_3)\rightarrow LL$), where the successors of a particular letter are determined using the MixGenerator(\overline{u}) pseudo-code. FIG. 8A depicts a schematic diagram of the trace of FIG. 8 having wafers positioned in position (1,1,0).

- D. Successor Generation That Includes Robot Position When the schedule generation routine includes robot movements, than to an n-chamber serial trace, comprised of chambers C_1, C_2, \ldots, C_n , the routine must associate a (n+1)-tuple from $\{0,1\}^n \times \{0,1,\ldots,n\}$. If \overline{x} is such a tuple, then, for $i=1,2,\ldots,n$, $\overline{x}[i]=0$, if chamber C_i is empty; and $\overline{x}[i]=1$, if C_i contains a wafer. Thus, as before, the first n-coordinates of \overline{x} are from $\{0,1\}$. The robot position is described by the last coordinate of \overline{x} , i.e., x_3 in the 3-tuple $(x_1,x_2;x_3)$, where x_1 and x_2 are wafer coordinates and x_3 is a robot coordinate. We set $\overline{x}[n+1]=k$ if (and only if) the robot is in a home position at chamber C_k . If $\overline{x}[n+1]=0$, the robot is positioned at the loadlock.
- Let S_n represent the alphabet of the above association. For example, if n=2, then S_2 is comprised of twelve 3-tuples, namely,

$$S_{2} = \{ (0,0;0), (0,0;1), (0,0;2); (0,1;0), (0,1;1), (0,1;2); \\ (1,0;0), (1,0;1), (1,0;2); (1,1;0), (1,1;1), (1,1;2) \}.$$

For an n-chamber serial trace, $|S_n|$ is the number of (n+1)-tuples from $\{0,1\}^n(\{0,1,\ldots,n\})$ and thus $|S_n|=(n+1)2^n$. These (n+1)-tuples are referred to as letters from the alphabet S_n . As before, a word is a finite string of letters from S_n . For example,

$$(0,0;0)$$
 $(1,0;1)$ $(0,1;2)$ $(0,1;0)$ $(1,1;1)$ $(1,1;2)$ $(1,0;0)$ $(1,0;1)$

30 is an 8-letter word. Note that a word may contain repeated letters. For example, abcdaxy is a word, but not a schedule.

In this representation, a schedule S is a word (a string of the above described (n+1)-tuples),

$S = \overline{xz} \cdots \overline{uv} \cdots \overline{yx},$

which starts and ends with the same letter and this is the only repeated letter. Furthermore, any two consecutive letters \overline{u} and \overline{v} (where \overline{v} is a successor of \overline{u}) differ in at most three coordinates and are related in accordance with the following rules:

- a) If $\overline{u}[1] = 0$ and $\overline{u}[n+1] = 0$, then $\overline{v}[1] = 1$ and $\overline{v}[n+1] = 1$. For all $i \notin \{1, n+1\}$, $\overline{v}[i] = \overline{u}[i]$. (This correspondence to a wafer being moved from the loadlock to C_1 .)
 - b) If $\overline{u}[n]=1$ and $\overline{u}[n+1]=n$, then $\overline{v}[n]=0$ and $\overline{v}[n+1]=0$. For all $i \notin \{n,n+1\}$, $\overline{v}[i]=\overline{u}[i]$. (This corresponds to a wafer being moved from C_n into the loadlock.)
- 15 c) If for some $r \notin \{0, n\}$, $\overline{u}[r] = 1$ and $\overline{u}[r+1] = 0$ and $\overline{u}[n+1] = r$, then $\overline{v}[r] = 0$ and $\overline{v}[r+1] = 1$ and $\overline{v}[n+1] = r+1$. For all $i \notin \{r, r+1, n+1\}$, $\overline{v}[i] = \overline{u}[i]$. (This corresponds to a wafer being moved from C_k into $C_{(k+1)}$, where neither C_k nor $C_{(k+1)}$ is a loadlock.)
- d) If $\overline{u}[1]=0$ and $\overline{u}[n+1]=j$ where $j\neq 0$, then $\overline{v}[n+1]=0$. For all $i\neq n+1$, $\overline{v}[i]=\overline{u}[i]$. (This corresponds to a robot moving from home position at C_j to a home position at a loadlock in preparation for a wafer moving from the loadlock into C_1 .)
- e) If $\overline{u}[n]=1$ and $\overline{u}[n+1]=j$ where $j\neq n$, then $\overline{v}[n+1]=n$. For all $i\neq n+1$, $\overline{v}[i]=\overline{u}[i]$. (This corresponds to a robot moving from a home position at C_j to a home position at C_n in preparation for a wafer move from C_n into loadlock.)
- f) If for some $r \notin \{0,n\}$, $\overline{u}[r]=1$ and $\overline{u}[r+1]=0$ and $\overline{u}[n+1]=j$ where $j \neq r$, then $\overline{v}[n+1]=r$. For all $i\neq n+1$, $\overline{v}[i]=\overline{u}[i]$. (This corresponds to a robot moving

from a home position at C_j to a home position at C_r in preparation for a wafer moving from C_r into C_{r+1} ; C_O represents the loadlock.)

- Note that rules (a), (b), and (c) above are, in fact rules (s_1) , (s_2) , and (s_3) , respectively, when the robot is already prepositioned to move a wafer, while (d), (e); and (f) correspond to prepositioning the robot for moves defined by rules (a), (b), and (c), respectively.
- A routine that calculates the number of successors of a given letter as well as finds and stores these successors is designed in a similar manner as in the previous cases for mixed and serial traces (this time by following the steps (a) through (f)). In such a routine, the number of
- successors is considerably large because, every time a wafer transfer is possible (e.g., $\overline{u}[i]=0$ or $\overline{u}[n]=1$ or $\overline{u}[i]=1$ and $\overline{u}[i+1]=0$, a robot may have to be prepositioned (e.g., from any of the n-1 positions $j\neq 0$ or $j\neq n$ or $j\neq i$). To achieve routines for determining the number of successors and the
- successors themselves that includes robot position, the new functions used are modifications of SerCount(\overline{u}) and SerGenerator(\overline{u}) (or MixCount(\overline{u}) and MixGenerator(\overline{u})). Given the foregoing description of SerCount(\overline{u}), SerGenerator(\overline{u}), MixCount(\overline{u}) and MixGenerator(\overline{u}), a person skilled in the
- 25 art could readily modify these functions to account for robot position using the aforementioned rules (a)-(f).
 - E. Generating Schedules From A Trace Using a Backtracking Technique
- Backtracking algorithms use special problem-tailored techniques to systematically explore implicitly directed graphs (usually trees). Such algorithms are well known in the art. In the schedule generation routine, a backtracking algorithm is used in conjunction with one or more of the
- previously discussed successor generation routines (e.g., SerGenerator(\overline{u}) or MixGenerator(\overline{u})) to produce every possible schedule given a particular trace.

10

Let \overline{u}_1 be the starting letter of a schedule. By using the rules for adding a successor letter as discussed in Sections B, C or D above, the foregoing routines build a partial schedule, say $S=\overline{u}_1\overline{u}_2\cdots\overline{u}_k$. There are two questions to answer every time a new letter \overline{u}_{k+1} is added to partial trace S:

- a) Is $\overline{u}_1\overline{u}_2 \cdots \overline{u}_k\overline{u}_{k+1}$ a full schedule?.
- b) If $\overline{u}_1\overline{u}_2\cdots\overline{u}_k\overline{u}_{k+1}$ is a full schedule, are there other full schedules which have not been recorded?

A word $\overline{u}_1\overline{u}_2...\overline{u}_{k+1}$ is recognized as a full schedule if it is built according to rules for successor letters and if there exists an index i<k+1 such that $\overline{u}_1=\overline{u}_{k+1}$ and all

letters \bar{u}_1 \bar{u}_2 \cdots \bar{u}_k are different. Thus, to determine a

15 full schedule a routine checks whether or not

$$\bar{u}_{k+1} \neq \bar{u}_i$$
, $i=1,2,\dots,k$,

for every newly appended letter \overline{u}_{k+1} which is a proper successor of \overline{u}_k .

Once it is found that $\overline{u}_1 = \overline{u}_{k+1}$ for some i<k+1, the 20 routine either prints or stores the full schedule \overline{u}_i $\overline{u}_{i+1} \dots \overline{u}_{k+1}$. To find other schedules, the routine removes \overline{u}_{k+1} from the full schedule S and looks at some other unused successor of \overline{u}_k . If there is such a successor, say letter \overline{z} , the routine checks if $\overline{u}_1 \dots \overline{u}_k \overline{z}$ is a full schedule. If

unused successors of \bar{z} and so on. If $\bar{u}_1 \dots \bar{u}_k \bar{z}$ is a full schedule, the routine removes \bar{z} and looks at another unused successor of \bar{u}_k . If there are no unused successors of \bar{u}_k , the routine goes back (backtrack) and looks at unused successors of \bar{u}_{k-1} and so on, until the routine returns to the starting letter \bar{u}_1 . Basically, the routine contains the following sequence of steps:

- (Initialize.) Choose the letter \overline{u}_1 of a schedule and go to Step 2.
- If schedule $\overline{u}_1\overline{u}_2\,\cdots\overline{u}_k$ is not complete, go to step 3. Else, go to Step 4.
- 5 Find a successor letter (of the last letter \bar{u}_k , in the schedule) which was not used, append it to the partial schedule and go to Step 2. If there are no unused successors, go to step 5.
 - 4. Print or store the schedule and go to Step 5.
- 5. If there are no more schedules, then STOP. Else, go 10 to Step 6.
 - (Backtrack.) Remove the last letter from the complete schedule and go to Step 3.
- 15 Clearly, the routine must ensure that it does not print (store) duplicate schedules in Step 4 as well as that the routine has printed (stored) all possible schedules. former is accomplished in Step 3 where the routine appends only an unused successor of the last letter to the partial
- 20 schedule. The latter is ensured by a proper termination condition (for example, the routine is at \overline{u}_1 (the initial letter) and there are no unused successors). It is convenient to choose the first letter \overline{u}_1 so that it has only one successor, e.g., $\overline{u}_1 = \overline{0}$ or $\overline{u}_1 = \overline{e}_1$, where \overline{e}_k is the k-th
- 25 column (row) of an n by n identity matrix.

For example, as illustrated in Fig. 9, starting with letter $\overline{\mathbf{0}}$, the routine builds a tree whose nodes are letters. If \overline{x} is such a node, the children of \overline{x} are successors of a letter \bar{x} and, for serial traces, there are exactly

- 30 SerCount(\bar{x}) of the successors. As such, the routine produces $\overline{0}$, $\overline{0}\overline{e}_1$ and $\overline{0}\overline{e}_1\overline{e}_2$ as successive partial schedules. (The word $\overline{0}\,\overline{e}_1\overline{e}_2$ is a directed path from node $\overline{0}$ to node \overline{e}_2 .) Since $\bar{e}_1 + \bar{e}_2$ and \bar{e}_3 are successors (children) of \bar{e}_2 , words $\bar{0}\,\bar{e}_1\bar{e}_2(\bar{e}_1+\bar{e}_2)$ and $\bar{0}\,\bar{e}_1\bar{e}_2\bar{e}_3$ are partial schedules as well.
- 35 Now, \bar{e}_3 has two successors $(\bar{e}_1 + \bar{e}_3 \text{ and } \bar{e}_4)$, while $\bar{e}_1 + \bar{e}_2$ has

only one successor $(\bar{e}_1+\bar{e}_3)$. Hence, $\bar{0}\bar{e}_1\bar{e}_2(\bar{e}_1+\bar{e}_2)(\bar{e}_1+\bar{e}_3)$ and $\bar{0}\bar{e}_1\bar{e}_2\bar{e}_3(\bar{e}_1+\bar{e}_3)$ and $\bar{0}\bar{e}_1\bar{e}_2\bar{e}_3\bar{e}_4$ are all partial schedules and so on.

As mentioned previously, letters comprising a given word (or partial schedule) S are distinguished by their positions; so S(1) is the first letter in S, S(2) is the second, and so on. The level of a search tree is denoted by L this is also the length of a partial schedule. Partial schedules of length L are thus paths of length L in a search

- tree. Function $\operatorname{scnt}(\bar{x})$ returns the number of successors of \bar{x} . As such $\operatorname{scnt}(\bar{x})$ is either $\operatorname{SerCount}(\bar{x})$ or $\operatorname{MixCount}(\bar{x})$ or either of these for a model which includes robot movements. If S is a partial schedule of length L, then S+w or Sw is a partial schedule of length L+1 and S(L+1)=w. Similarly, if
- 15 length of S is L and S(L)=w, then S-w has length L-1 (in short, + means append a letter and - means remove a letter).

Finally, a commitment to data organization (structure) is necessary in an efficiently designed routine. Keep in mind that the number of chambers (and thus the number of

- successors of a given word) is relatively small. Thus, it does not make any difference if the routine generates all successors of a given letter and stores them, as opposed to dynamically generating the successors one-by-one as the need arises.
- A basic schedule generator routine can be summarized by the following five steps:
 - 1. Initialize the schedule: $S \leftarrow \overline{0}$ and $L \leftarrow 1$ and go to Step 2.
- 2. $\bar{x} \leftarrow S(L)$ and $\delta \leftarrow cnt(\bar{x})$. Store δ successors of \bar{x} , $\bar{y}_1, \bar{y}_2, ..., \bar{y}_{\delta}$, and mark them unused. Go to Step 3.
 - 3. S \leftarrow S + $\bar{y_i}$ and L \leftarrow L + 1 and $\delta \leftarrow \delta$ 1. Mark $\bar{y_i}$ used and go to Step 4.
- 4. Compare S(L) with S(1), S(2),...,S(L-1),
 respectively. If S(i)=S(L) for some i<1, print S
 and L and go to Step 5; else, go to Step 2.

5

 S←S-S(L) and L←L-1. If L=1, STOP; else, go to Step 6.

6. If δ =0, go to Step 5. Else (δ >0), append an unused successor of S(L) to S, mark it used, δ + δ -1, and go to Step 2.

In step 1, the routine initializes the schedule, S, and the level of the search tree, L. Clearly, L must be initialized to 1. As for the initial letter in schedule S, for convenience, the routine uses a letter that has only one successor. A letter $\overline{0}$ corresponds to a situation in which all chambers are empty (i.e., the tool has just begun processing wafers).

In step 2, the routine first finds the number of successors, δ , of the last letter, say \bar{x} , in a partial schedule $S(\text{clearly}, \bar{x}=S(1))$. Function $\text{cnt}(\bar{x})$ returns the number of successors of a given letter \bar{x} . Then, by using the rules which determine the successor of a given letter, the routine finds, stores and marks unused successors of \bar{x} .

As a result, a successor may be a record with two fields: the first field is the actual letter, while the second field is a Boolean variable with value true if the successor was not used in a particular partial schedule S and value false otherwise. (Or the routine may use a matrix representation

25 for the list of successors as described in Sections C and D above.)

In step 3, one of the unused successors of the last letter \bar{x} is appended to the partial schedule S, the length of schedule L is increased by 1 and the number of unused successors of \bar{x} is decreased by 1. (There will always be at least one successor to any given letter.)

In step 4, the routine checks if S is a full schedule by comparing the newly added (the last) letter S(L) with all previous letters S(1),S(2),...,S(L-1). (That should be accomplished every time a new letter is appended to a partial schedule.) If S(L) is a repeated letter, the

routine prints (stores) the schedule; else, the routine continues with building the schedule.

When a partial schedule becomes a full schedule, S(1)S(2)...S(L), after storing the schedule, the routine removes the last letter S(L) and look for some other unused successor of S(L-1). If there are some unused successors, the routine appends a successor to the partial schedule, finds its successors, appends one of these successors and so on. If there are no successors, the routine removes S(L-1) from S and looks for unused successors of S(L-2) and so on. The program terminates when L=1 and $\delta=0$ (meaning there are no unused successors of the first letter).

The routine above is valid for any representation of the scheduling problem. That is, either serial or mixed traces with letters from $\{0,1\}^n$ or either of these traces with robot position being part of the model (and thus

alphabet from $\{0,1\}^n \times \{0,1,\ldots,n\}$). Clearly, functions that count and generate successors of a given letter are different each time.

Fig. 10 depicts a flow diagram of a schedule generation routine 1000 that operates as generally discussed above. The routine 1000 begins at step 1002 by initializing the schedule, e.g., setting an initial letter to an n-tuple (n-string) of zeros. At step 1004, the routine finds,

- stores and marks all unused successors of the last letter in a partial schedule. The successor letters are determined using the pseudo-code routines SerGenerator, ParGenerator and MixGenerator and the number of successor letters for each letter is determined using SerCount, ParCount and
- MixCount. Of course, as mentioned above, if the robot position is to be taken into account, these pseudo-code routines must be appropriately modified to accommodate the expanded letters and the modify rules of successor generation.
- 35 Then, at step 1006, the routine appends an unused successor of the last letter to a partial schedule as well as increases the length of the schedule by one and decreases the number of unused successors by one. The routine

PCT/US98/11320

queries, at step 1008, whether the last letter of the partial trace has been reached. If the query is negatively answered, the routine proceeds along the NO path to step 1004. If the query is affirmatively answered, the routine 5 proceeds to step 1010 where the schedule is either printed or stored.

Steps 1012, 1014, 1016 and 1018 represent a backtracking process. At step 1012, the routine removes the last letter of the schedule to produce a partial schedule 10 and reduce the schedule length by one. Then, at step 1014, the routine queries whether the length of schedule is one. If the query is affirmatively answered, the routine stops at step 1016. However, if the query is negatively answered, the routine proceeds to step 1018. At step 1018, the 15 routine queries whether there is an unused successor to the last letter. If the query is negatively answered, the routine proceeds along the NO path to step 1012. Otherwise, the routine proceeds to step 1020 where an unused successor is appended to the partial schedule. The routine then 20 returns to step 1004.

Once all possible schedules are determined and stored in memory, the schedules are processed by a conventional throughput model. Specifically, each schedule is used by the model to predict a throughput for that schedule. 25 throughputs for all the schedules are compared to find the schedule having the highest (best) throughput. The schedule with the highest throughput is deemed optimal and is used to control the sequencer. The throughput model may be executed upon the sequencer computer or, more likely, it is executed 30 on a remote computer, and the optimal schedule is downloaded to the sequencer.

The present invention rapidly computes all possible schedules for a given cluster tool configuration. schedules are then executed by a conventional throughput 35 model to determine the optimal schedule. As such, the present invention facilitates automatic determination of an optimal schedule in a rapid and accurate manner that has heretofore been unavailable in the prior art.

Although various embodiments which incorporate the teachings of the present invention have been shown and described in detail herein, those skilled in the art can readily devise many of the varied embodiments that still incorporate these teachings.

What is claimed is:

- A method of producing schedules for processing a wafer
 in a multichamber semiconductor wafer processing tool comprising the steps of:
 - (a) providing a trace defining a series of chambers that are visited by a wafer as the wafer is processed by the tool;
- '(b) initializing a sequence generator with an initial value of a variable defining an initial wafer positioning with the tool; and
- (c) generating values of said variable that represent all valid successor wafer positions related to the initial value, where said values of said variable, taken together, form a partial schedule for processing a wafer.
- The method of claim 1 further comprising a step of computing a total number of variable values generated from a
 given variable value.
 - 3. The method of claim 1 further comprising the steps of:
- (d) backtracking through said series of variable values in said partial schedule and applying step (c) to each value
 25 in said partial schedule to produce further values of said variable representing additional series of values that represent additional partial schedules: and
- (e) stopping said backtracking when all possible variable value combinations are produced that represent all30 possible valid schedules for said trace.
 - 4. The method of claim 1 wherein a value of said variable is a letter and a plurality of letters forms a word.
- 35 5. The method of claim 4 wherein a valid schedule is defined by a word having no more than one repeated letter.

- 6. The method of claim 4 wherein each letter contains a n-tuple, where n represents a total number of wafer positions within said trace.
- 5 7. The method of claim 6 wherein n represents a total number of wafer positions within said trace plus a transport robot position.
- 8. The method of claim 3 further comprising the step of:
 10 '(f) identifying at least one schedule in all possible
 - valid schedules that provides an optimal throughput for the trace.
- 9. The method of claim 8 wherein said identifying step (f) further comprises the step of computing the throughput for each and every schedule of said all possible schedules and selecting an optimum schedule for the trace which produces the highest throughput.
- 20 10. The method of claim 3 wherein said backtracking step (d) further comprises the steps of:
 - (a') initializing a schedule to an n-string of zeros having a length of one;
- (b') identifying all unused successors of a last letter
 25 in a partial schedule;
 - (c') appending an unused successor to said partial
 schedule;
 - (d') increasing the length of the partial schedule by one and decreasing a number of unused successors by one;
- (e') querying whether the last letter of the partial schedule is the same as a previous letter in the partial schedule and, if not, repeat steps (b'), (c'), (d') and (e') until the last letter of the partial schedule is the same as a previous letter in the partial schedule;
- 35 (f') storing the partial schedule as a full schedule and storing the length of the full schedule;
 - (g') removing the last letter of the full schedule to produce a new partial schedule and decreasing the length of the full schedule by one;

PCT/US98/11320 WO 98/57358 -30-

(h') querying whether the length of the new partial schedule is one and, if the length is one, stopping; otherwise, proceeding to step (i');

- (i') querying whether there is an unused successor of 5 the last letter and, if there are no unused successors of the last letter, repeating steps (g'), (h') and (i') until there is an unused successor of the last letter;
- (j') appending the unused successor to the new partial schedule, marking the successor as used and decreasing the 10 number of successors by one; and
 - (k') returning to step (b').
- The method of claim 1 wherein successor variables values are defined by successor generation rules that are 15 prescribed by wafer processing parameters.
 - The method of claim 1 wherein successor variable values are generated with regard to transport robot positioning.
- 20 13. Apparatus for producing schedules for processing a wafer in a multichamber semiconductor wafer processing tool, having a trace defining a series of chambers that are visited by a wafer as the wafer is processed by the tool, said apparatus comprising:
- a sequence generator, being initialized with an initial 25 value of a variable defining an initial wafer positioning within the tool, for generating values of said variable that represent all valid successor wafer positions related to the initial value, where said values of said variable, taken 30 together, form a partial schedule for processing a wafer.
 - The apparatus of claim 13 further comprising means for computing a total number of successor variable values generated from a given variable value.

35

The apparatus of claim 13 further comprising: 15. means for backtracking through said series of variable values in said partial sequence and selecting each value in said partial schedule as an input to said sequence generator which produces further values of said variable representing additional series of values that represent additional partial schedules, whereby all possible schedules for said trace are generated.

5

16. The apparatus of claim 15 further comprising a throughput model, coupled to said sequence generator, for computing a throughput value for each possible schedule in said all possible schedules.

10

- 17. The apparatus of claim 16 further comprising means for identifying at least one schedule that has the largest throughput value.
- 15 18. A schedule data structure, stored in a computer readable storage medium, of a schedule for processing a wafer in a multichamber semiconductor wafer processing tool comprising:
- a plurality of n-tuples, where n is a total number of possible wafer positions, and the plurality of n-tuples contains only one duplicate n-tuple.
- 19. The schedule data structure of claim 18 wherein n is a total number of possible wafer positions plus a position of transport robot position.
- 20. The schedule data structure of claim 18 wherein the n-tuple has a form $(x_1, x_2, x_3, \ldots, x_n)$, where x defines the contents of a particular chamber at a particular point in a schedule and x has a value 0 when a wafer is not positioned in the chamber and a value of 1 when a wafer is positioned in the chamber.

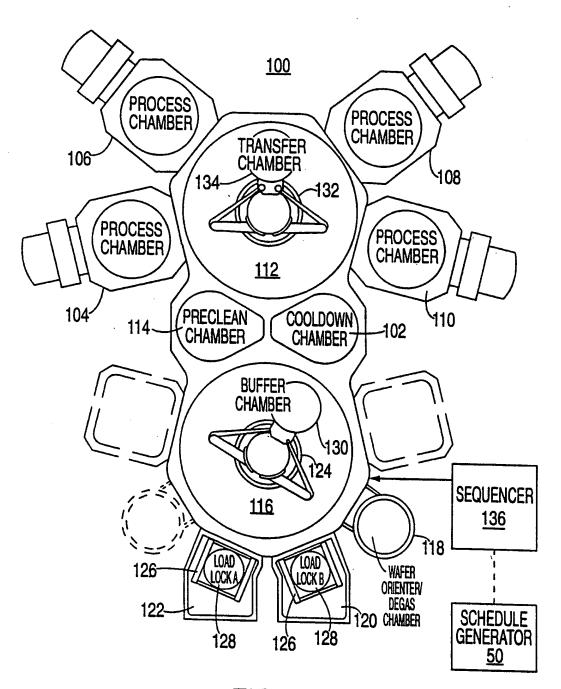


FIG. 1

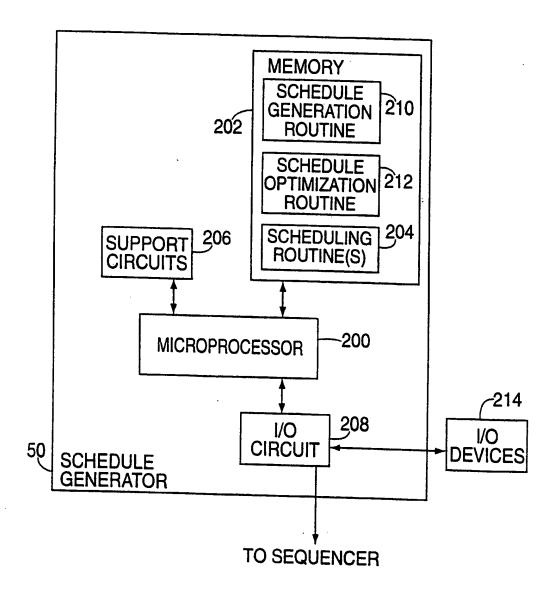
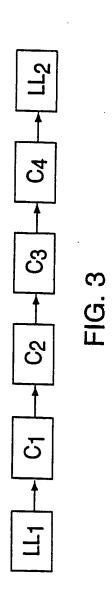
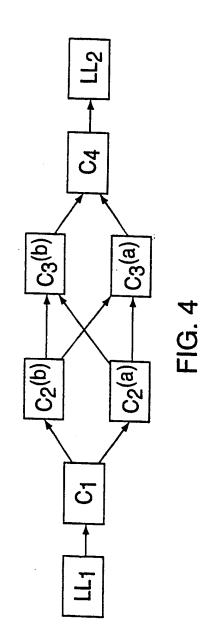
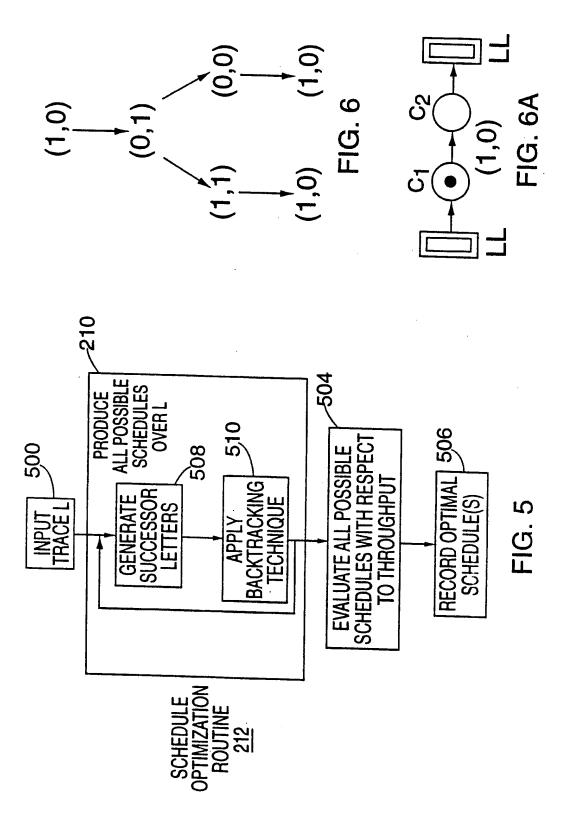
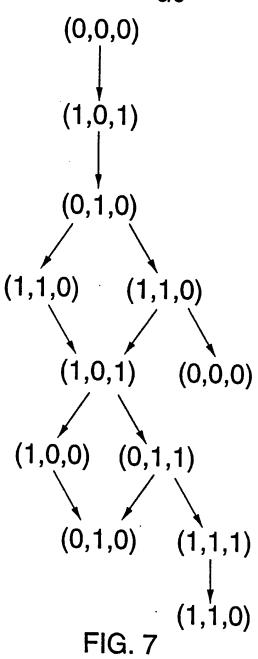


FIG. 2

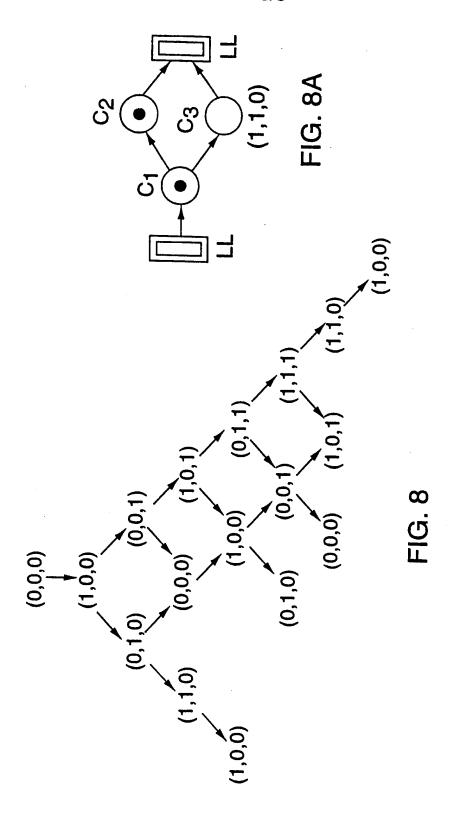


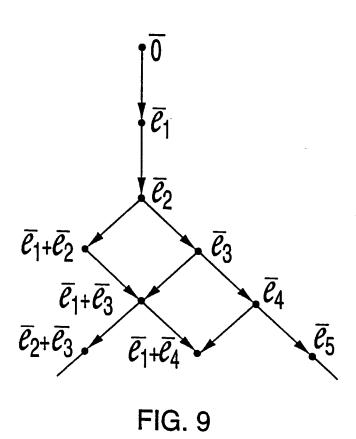


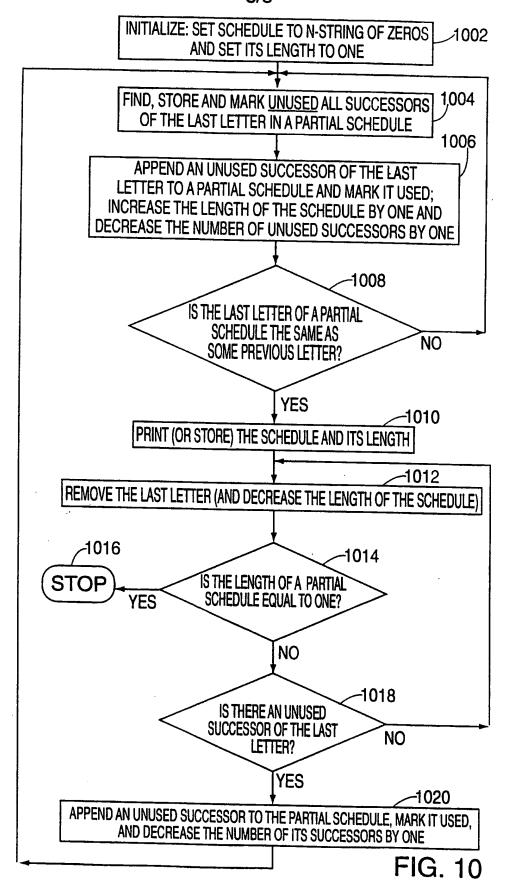




$$\begin{array}{c|cccc}
C_1 & C_2 & C_3 \\
\hline
 & & & & & \\
\hline
 & & & & & \\
 & & & & & \\
\hline
 & & & & & \\
 & & & & & \\
\hline
 & & & & & \\
 & & & & & \\
\hline
 & & & & \\
\hline
 & & & & \\
\hline
 & & & & \\
\hline
 & & & & \\
\hline
 & & & & & \\$$







INTERNATIONAL SEARCH REPORT

in ational Application No

		P	CT/US 98/11320 -	
A. CLASSI IPC 6	FICATION OF SUBJECT MATTER H01L21/00 G05B19/418			
	400013, 120			
	o International Patent Classification(IPC) or to both national classifica SEARCHED	tion and IPC		
	SEARCHED Cumeritation searched (classification system followed by classification	n symbols)		
IPC 6	HO1L G05B			
Documentat	tion searched other than minimum documentation to the extent that su	ch documents are included	in the fields searched	
Electronic d	ata base consulted during the international search (name of data bas	e and, where practical, sea	rch terms used)	
	·			
C. DOCUME	ENTS CONSIDERED TO BE RELEVANT	·	·	
Category °	Citation of document, with indication, where appropriate, of the rele	vant passages	Relevant to claim No.	
	, and appropriate, or the loss	rain pasaagas	Helevalii to Claiin No.	
Α	US 4 896 269 A (TONG) 23 January	1990	1,13,18	
	see the whole document		3,55,15	
Α	PATENT ABSTRACTS OF JAPAN		1	
	vol. 96, no. 2, 29 February 1996		1	
	& JP 07 283093 A (TOKYO ELECTRON	LTD),		
	27 October 1995 see abstract			
Α	PATENT ABSTRACTS OF JAPAN		1	
	vol. 96, no. 1, 31 January 1996			
•	& JP 07 237095 A (HITACHI LTD), 12 September 1995		İ	
	see abstract			
				
:	•			
			·	
<u></u>	ner documents are listed in the continuation of box C.	X Patent family mem	bers are listed in annex.	
	tegories of cited documents :	"T" later document publish	ed after the international filing date	
"A" document defining the general state of the art which is not cited to understand the principle or to considered to be of particular relevance.			t in conflict with the application but	
"E" earlier document but published on or after the international "X" document of filing date			relevance; the claimed invention	
"L" document which may throw doubts on priority claim(s) or involve an inventive step when the document is taken alone				
citation or other special reason (as specified) cannot be considered to involve an invention cannot be considered to involve an inventive step when the				
other means ments, such combination being obvious to a person skilled				
later th	ant published prior to the international filing date but an the priority date claimed	in the art. &" document member of the same patent family		
Date of the actual completion of the international search Date of mailing of the international search report				
8	October 1998	15/10/1998		
Name and n	nailing address of the ISA	Authorized officer		
	European Patent Office, P.B. 5818 Patentiaan 2 NL - 2280 HV Rijswijk			
	Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016	Bolder, G	· !	

INTERNATIONAL SEARCH REPORT

Information on patent family members

im itional Application No PCT/US 98/11320

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
US 4896269 A	23-01-1990	NONE	
			·